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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	HDMI-CEC, I²C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	DMA, I²S, POR, PWM, WDT
Number of I/O	36
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 13x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	49-UFBGA, WLCSP
Supplier Device Package	49-WLCSP
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f078cby6tr

Table 1. STM32F078CB/RB/VB family device features and peripheral counts

Peripheral		STM32F078CB	STM32F078RB	STM32F078VB
Flash memory (Kbyte)		128		
SRAM (Kbyte)		16		
Timers	Advanced control	1 (16-bit)		
	General purpose	5 (16-bit) 1 (32-bit)		
	Basic	2 (16-bit)		
Comm. interfaces	SPI [I^2S](1)	2 [2]		
	I^2C	2		
	USART	4		
	USB	1		
	CEC	1		
12-bit ADC (number of channels)		1 (10 ext. + 3 int.)	1 (16 ext. + 3 int.)	
12-bit DAC (number of channels)		1 (2)		
Analog comparator		2		
GPIOs		36	50	86
Capacitive sensing channels		16	17	23
Max. CPU frequency		48 MHz		
Operating voltage		V_{DD} = 1.8 V ± 8%, V_{DDA} = from V_{DD} to 3.6 V		
Operating temperature		Ambient operating temperature: -40°C to 85°C / -40°C to 105°C Junction temperature: -40°C to 105°C / -40°C to 125°C		
Packages		LQFP48 UFQFPN48 WLCSP49	LQFP64	LQFP100 UFBGA100

1. The SPI interface can be used either in SPI mode or in I^2S audio mode.

3.4 Cyclic redundancy check calculation unit (CRC)

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code using a configurable generator polynomial value and size.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a signature of the software during runtime, to be compared with a reference signature generated at link-time and stored at a given memory location.

3.5 Power management

3.5.1 Power supply schemes

- V_{DD} = V_{DDIO1} = 1.8 V ± 8%: external power supply for I/Os (V_{DDIO1}) and digital logic. It is provided externally through VDD pins.
- V_{DDA} = from V_{DD} to 3.6 V: external analog power supply for ADC, DAC, RCs and PLL (minimum voltage to be applied to V_{DDA} is 2.4 V when the ADC or DAC are used). It is provided externally through VDDA pin. The V_{DDA} voltage level must be always greater or equal to the V_{DD} voltage level and must be established first.
- V_{DDIO2} = 1.65 to 3.6 V: external power supply for marked I/Os. V_{DDIO2} is provided externally through the VDDIO2 pin. The V_{DDIO2} voltage level is completely independent from V_{DD} or V_{DDA}, but it must not be provided without a valid supply on V_{DD}. The V_{DDIO2} supply is monitored and compared with the internal reference voltage (V_{REFINT}). When the V_{DDIO2} is below this threshold, all the I/Os supplied from this rail are disabled by hardware. The output of this comparator is connected to EXTI line 31 and it can be used to generate an interrupt. Refer to the pinout diagrams or tables for concerned I/Os list.
- V_{BAT} = 1.65 to 3.6 V: power supply for RTC, external clock 32 kHz oscillator and backup registers (through power switch) when V_{DD} is not present.

For more details on how to connect power pins, refer to *Figure 12: Power supply scheme*.

3.5.2 Power-on reset

To guarantee a proper power-on reset, the NPOR pin must be held low until V_{DD} is stable. When V_{DD} is stable, the reset state can be exited either by:

- putting the NPOR pin in high impedance (NPOR pin has an internal pull-up), or by
- forcing the pin to high level by connecting it to V_{DDA}

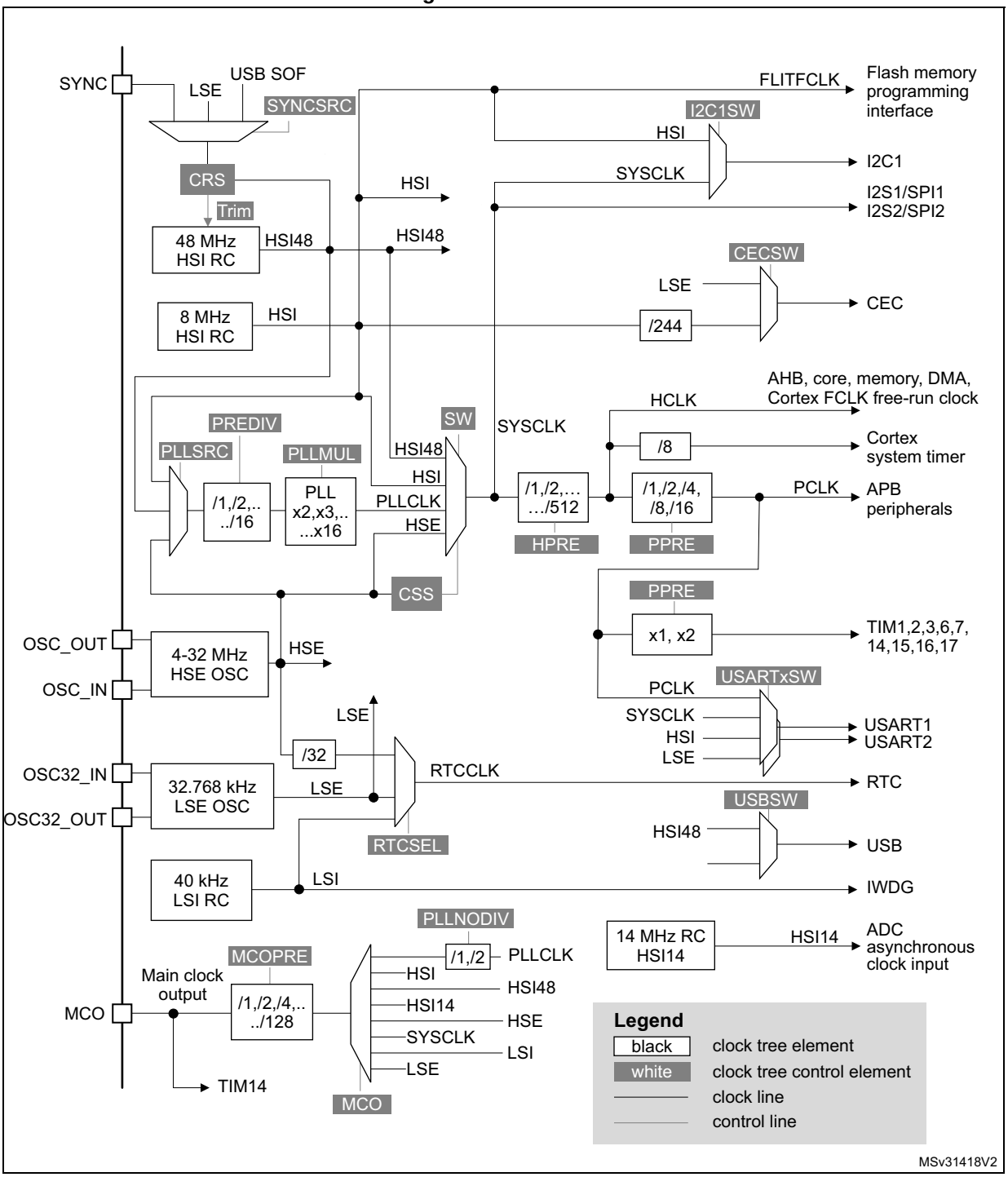
3.5.3 Low-power modes

The STM32F078CB/RB/VB microcontrollers support two low-power modes to achieve the best compromise between low power consumption, short startup time and available wakeup sources:

- **Sleep mode**

  In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs.

Figure 2. Clock tree



3.7 General-purpose inputs/outputs (GPIOs)

Each of the GPIO pins can be configured by software as output (push-pull or open-drain), as input (with or without pull-up or pull-down) or as peripheral alternate function. Most of the GPIO pins are shared with digital or analog alternate functions.

Table 5. Number of capacitive sensing channels available on STM32F078CB/RB/VB devices (continued)

Analog I/O group	Number of capacitive sensing channels		
	STM32F078Vx	STM32F078Rx	STM32F078Cx
G5	3	3	3
G6	3	3	3
G7	3	0	0
G8	3	0	0
Number of capacitive sensing channels	23	17	16

3.14 Timers and watchdogs

The STM32F078CB/RB/VB devices include up to six general-purpose timers, two basic timers and an advanced control timer.

Table 6 compares the features of the different timers.

Table 6. Timer feature comparison

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
Advanced control	TIM1	16-bit	Up, down, up/down	integer from 1 to 65536	Yes	4	3
General purpose	TIM2	32-bit	Up, down, up/down	integer from 1 to 65536	Yes	4	-
	TIM3	16-bit	Up, down, up/down	integer from 1 to 65536	Yes	4	-
	TIM14	16-bit	Up	integer from 1 to 65536	No	1	-
	TIM15	16-bit	Up	integer from 1 to 65536	Yes	2	1
	TIM16 TIM17	16-bit	Up	integer from 1 to 65536	Yes	1	1
Basic	TIM6 TIM7	16-bit	Up	integer from 1 to 65536	Yes	-	-

3.14.1 Advanced-control timer (TIM1)

The advanced-control timer (TIM1) can be seen as a three-phase PWM multiplexed on six channels. It has complementary PWM outputs with programmable inserted dead times. It

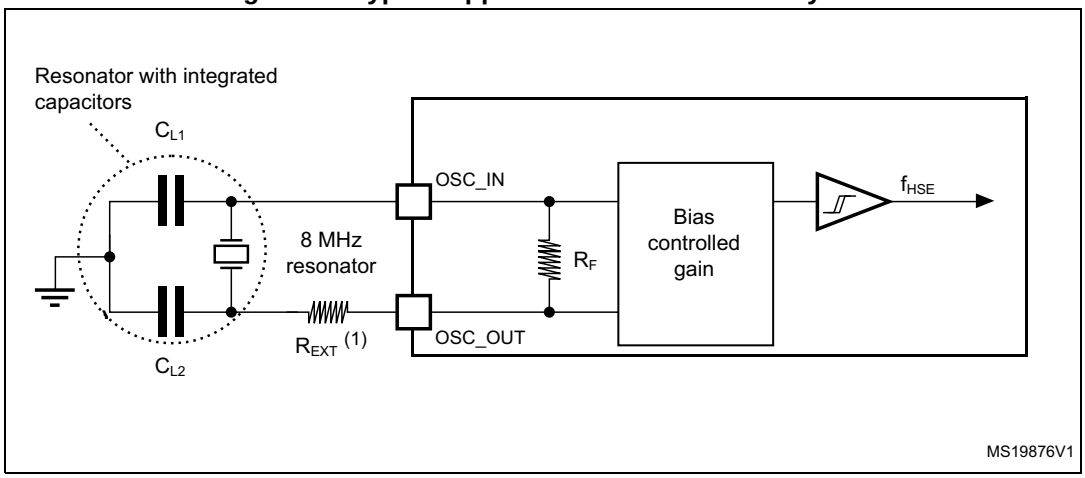
Table 12. STM32F078CB/RB/VB pin definitions (continued)

Pin numbers					Pin name (function upon reset)	Pin type	I/O structure	Notes	Pin functions	
UFBGA100	LQFP100	LQFP64	LQFP48/UFQFPN48	WLCSP49					Alternate functions	Additional functions
C1	7	2	2	D5	PC13	I/O	TC	(1) (2)	-	WKUP2, RTC_TAMP1, RTC_TS, RTC_OUT
D1	8	3	3	C7	PC14-OSC32_IN (PC14)	I/O	TC	(1) (2)	-	OSC32_IN
E1	9	4	4	C6	PC15-OSC32_OUT (PC15)	I/O	TC	(1) (2)	-	OSC32_OUT
F2	10	-	-	-	PF9	I/O	FT	-	TIM15_CH1	-
G2	11	-	-	-	PF10	I/O	FT	-	TIM15_CH2	-
F1	12	5	5	D7	PF0-OSC_IN (PF0)	I/O	FT	-	CRS_ SYNC	OSC_IN
G1	13	6	6	D6	PF1-OSC_OUT (PF1)	I/O	FT	-	-	OSC_OUT
H2	14	7	7	E7	NRST	I/O	RST	-	Device reset input / internal reset output (active low)	
H1	15	8	-	-	PC0	I/O	TTa	-	EVENTOUT	ADC_IN10
J2	16	9	-	-	PC1	I/O	TTa	-	EVENTOUT	ADC_IN11
J3	17	10	-	-	PC2	I/O	TTa	-	SPI2_MISO, I2S2_MCK, EVENTOUT	ADC_IN12
K2	18	11	-	-	PC3	I/O	TTa	-	SPI2_MOSI, I2S2_SD, EVENTOUT	ADC_IN13
J1	19	-	-	-	PF2	I/O	FT	-	EVENTOUT	WKUP8
K1	20	12	8	E6	VSSA	S	-	-	Analog ground	
M1	21	13	9	F7	VDDA	S	-	-	Analog power supply	
L1	22	-	-	-	PF3	I/O	FT	-	EVENTOUT	
L2	23	14	10	F6	PA0	I/O	TTa	-	USART2_CTS, TIM2_CH1_ETR, TSC_G1_IO1, USART4_TX	RTC_ TAMP2, WKUP1, COMP1_OUT, ADC_IN0, COMP1_INM6

Table 12. STM32F078CB/RB/VB pin definitions (continued)

Pin numbers					Pin name (function upon reset)	Pin type	I/O structure	Notes	Pin functions	
UFBGA100	LQFP100	LQFP64	LQFP48/UFQFPN48	WLCSP49					Alternate functions	Additional functions
M6	36	27	19	G4	PB1	I/O	TTa	-	TIM3_CH4, USART3_RTS, TIM14_CH1, TIM1_CH3N, TSC_G3_IO3	ADC_IN9
L6	37	28	20	G3	NPOR	I	POR	(3)	Device power-on reset input (active low)	
M7	38	-	-	-	PE7	I/O	FT	-	TIM1_ETR	-
L7	39	-	-	-	PE8	I/O	FT	-	TIM1_CH1N	-
M8	40	-	-	-	PE9	I/O	FT	-	TIM1_CH1	-
L8	41	-	-	-	PE10	I/O	FT	-	TIM1_CH2N	-
M9	42	-	-	-	PE11	I/O	FT	-	TIM1_CH2	-
L9	43	-	-	-	PE12	I/O	FT	-	SPI1_NSS, I2S1_WS, TIM1_CH3N	-
M10	44	-	-	-	PE13	I/O	FT	-	SPI1_SCK, I2S1_CK, TIM1_CH3	-
M11	45	-	-	-	PE14	I/O	FT	-	SPI1_MISO, I2S1_MCK, TIM1_CH4	-
M12	46	-	-	-	PE15	I/O	FT	-	SPI1_MOSI, I2S1_SD, TIM1_BKIN	-
L10	47	29	21	E3	PB10	I/O	FT	-	SPI2_SCK, I2C2_SCL, USART3_TX, CEC, TSC_SYNC, TIM2_CH3	-
L11	48	30	22	G2	PB11	I/O	FT	-	USART3_RX, TIM2_CH4, EVENTOUT, TSC_G6_IO1, I2C2_SDA	-
F12	49	31	23	D3	VSS	S	-	-	Ground	
G12	50	32	24	F2	VDD	S	-	-	Digital power supply	
L12	51	33	25	E2	PB12	I/O	FT	-	TIM1_BKIN, TIM15_BKIN, SPI2_NSS, I2S2_WS, USART3_CK, TSC_G6_IO2, EVENTOUT	-
K12	52	34	26	G1	PB13	I/O	FTf	-	SPI2_SCK, I2S2_CK, I2C2_SCL, USART3_CTS, TIM1_CH1N, TSC_G6_IO3	-

Figure 16. Typical application with an 8 MHz crystal



1. R_{EXT} value depends on the crystal characteristics.

Low-speed external clock generated from a crystal resonator

The low-speed external (LSE) clock can be supplied with a 32.768 kHz crystal resonator oscillator. All the information given in this paragraph are based on design simulation results obtained with typical external components specified in *Table 37*. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

Table 37. LSE oscillator characteristics (f_{LSE} = 32.768 kHz)

Symbol	Parameter	Conditions(1)	Min(2)	Typ	Max(2)	Unit
I_{DD}	LSE current consumption	low drive capability	-	0.5	0.9	µA
		medium-low drive capability	-	-	1	
		medium-high drive capability	-	-	1.3	
		high drive capability	-	-	1.6	
g_m	Oscillator transconductance	low drive capability	5	-	-	µA/V
		medium-low drive capability	8	-	-	
		medium-high drive capability	15	-	-	
		high drive capability	25	-	-	
$t_{SU(LSE)}$(3)	Startup time	V_{DDIOx} is stabilized	-	2	-	s

1. Refer to the note and caution paragraphs below the table, and to the application note AN2867 “Oscillator design guide for ST microcontrollers”.
2. Guaranteed by design, not tested in production.
3. $t_{SU(LSE)}$ is the startup time measured from the moment it is enabled (by software) to a stabilized 32.768 kHz oscillation is reached. This value is measured for a standard crystal and it can vary significantly with the crystal manufacturer

Table 47. ESD absolute maximum ratings

Symbol	Ratings	Conditions	Packages	Class	Maximum value(1)	Unit
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	T_A = +25 °C, conforming to JESD22-A114	All	2	2000	V
$V_{ESD(CDM)}$	Electrostatic discharge voltage (charge device model)	T_A = +25 °C, conforming to ANSI/ESD STM5.3.1	WLCSP49	C3	250	V
			All others	C4	500	

1. Data based on characterization results, not tested in production.

Static latch-up

Two complementary static tests are required on six parts to assess the latch-up performance:

- A supply overvoltage is applied to each power supply pin.
- A current injection is applied to each input, output and configurable I/O pin.

These tests are compliant with EIA/JESD 78A IC latch-up standard.

Table 48. Electrical sensitivities

Symbol	Parameter	Conditions	Class
LU	Static latch-up class	T_A = +105 °C conforming to JESD78A	II level A

6.3.12 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below V_{SS} or above V_{DDIOx} (for standard, 3.3 V-capable I/O pins) should be avoided during normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during device characterization.

Functional susceptibility to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error above a certain limit (higher than 5 LSB TUE), out of conventional limits of induced leakage current on adjacent pins (out of the -5 µA/+0 µA range) or other functional failure (for example reset occurrence or oscillator frequency deviation).

The characterization results are given in *Table 49*.

Negative induced leakage current is caused by negative injection and positive induced leakage current is caused by positive injection.

Output driving current

The GPIOs (general purpose input/outputs) can sink or source up to +/-8 mA, and sink or source up to +/- 20 mA (with a relaxed V_{OL}/V_{OH}).

In the user application, the number of I/O pins which can drive current must be limited to respect the absolute maximum rating specified in *Section 6.2*:

- The sum of the currents sourced by all the I/Os on V_{DDIOx}, plus the maximum consumption of the MCU sourced on V_{DD}, cannot exceed the absolute maximum rating ΣI_{VDD} (see *Table 20: Voltage characteristics*).
- The sum of the currents sunk by all the I/Os on V_{SS}, plus the maximum consumption of the MCU sunk on V_{SS}, cannot exceed the absolute maximum rating ΣI_{VSS} (see *Table 20: Voltage characteristics*).

Output voltage levels

Unless otherwise specified, the parameters given in the table below are derived from tests performed under the ambient temperature and supply voltage conditions summarized in *Table 23: General operating conditions*. All I/Os are CMOS- and TTL-compliant (FT, TTa or TC unless otherwise specified).

Table 51. Output voltage characteristics(1)

Symbol	Parameter	Conditions	Min	Max	Unit
V_{OL}	Output low level voltage for an I/O pin	CMOS port(2) $\|I_{IO}\|$ = 8 mA $V_{DDIOx} \geq 2.7$ V	-	0.4	V
V_{OH}	Output high level voltage for an I/O pin		V_{DDIOx}–0.4	-	
V_{OL}	Output low level voltage for an I/O pin	TTL port(2) $\|I_{IO}\|$ = 8 mA $V_{DDIOx} \geq 2.7$ V	-	0.4	V
V_{OH}	Output high level voltage for an I/O pin		2.4	-	
V_{OL}(3)	Output low level voltage for an I/O pin	$\|I_{IO}\|$ = 20 mA $V_{DDIOx} \geq 2.7$ V	-	1.3	V
V_{OH}(3)	Output high level voltage for an I/O pin		V_{DDIOx}–1.3	-	
V_{OL}(3)	Output low level voltage for an I/O pin	$\|I_{IO}\|$ = 6 mA $V_{DDIOx} \geq 2$ V	-	0.4	V
V_{OH}(3)	Output high level voltage for an I/O pin		V_{DDIOx}–0.4	-	
V_{OL}(4)	Output low level voltage for an I/O pin	$\|I_{IO}\|$ = 4 mA	-	0.4	V
V_{OH}(4)	Output high level voltage for an I/O pin		V_{DDIOx}–0.4	-	V
V_{OLFm+}(3)	Output low level voltage for an FTf I/O pin in Fm+ mode	$\|I_{IO}\|$ = 20 mA $V_{DDIOx} \geq 2.7$ V	-	0.4	V
		$\|I_{IO}\|$ = 10 mA	-	0.4	V

1. The I_{IO} current sourced or sunk by the device must always respect the absolute maximum rating specified in *Table 20: Voltage characteristics*, and the sum of the currents sourced or sunk by all the I/Os (I/O ports and control pins) must always respect the absolute maximum ratings ΣI_{IO}.
2. TTL and CMOS outputs are compatible with JEDEC standards JESD36 and JESD52.
3. Data based on characterization results. Not tested in production.
4. Data based on characterization results. Not tested in production.

Table 54. NPOR pin characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IL(NPOR)}$	NPOR Input low level voltage	-	-	-	0.475 V_{DDA} - 0.2(1)	V
$V_{IH(NPOR)}$	NPOR Input high level voltage	-	0.5 V_{DDA} + 0.2(1)	-	-	
$V_{hys(NPOR)}$	NPOR Schmitt trigger voltage hysteresis	-	-	100(1)	-	mV
R_{PU}	Weak pull-up equivalent resistor(2)	$V_{IN} = V_{SS}$	25	40	55	kΩ

1. Guaranteed by design, not tested in production.
2. The pull-up is designed with a true resistance in series with a switchable PMOS. This PMOS contribution to the series resistance is minimal (~10% order).

6.3.15 12-bit ADC characteristics

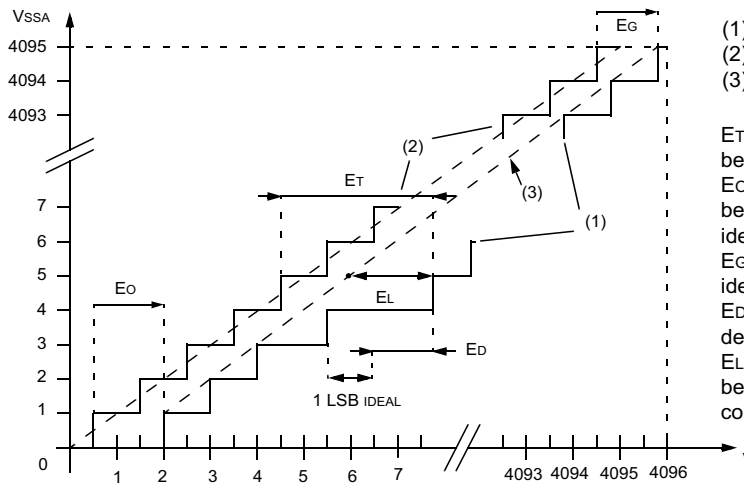
Unless otherwise specified, the parameters given in *Table 55* are derived from tests performed under the conditions summarized in *Table 23: General operating conditions*.

Note: It is recommended to perform a calibration after each power-up.

Table 55. ADC characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DDA}	Analog supply voltage for ADC ON	-	2.4	-	3.6	V
$I_{DDA\ (ADC)}$	Current consumption of the ADC(1)	V_{DDA} = 3.3 V	-	0.9	-	mA
f_{ADC}	ADC clock frequency	-	0.6	-	14	MHz
f_S(2)	Sampling rate	12-bit resolution	0.043	-	1	MHz
f_{TRIG}(2)	External trigger frequency	f_{ADC} = 14 MHz, 12-bit resolution	-	-	823	kHz
		12-bit resolution	-	-	17	$1/f_{ADC}$
V_{AIN}	Conversion voltage range	-	0	-	V_{DDA}	V
R_{AIN}(2)	External input impedance	See *Equation 1* and *Table 56* for details	-	-	50	kΩ
R_{ADC}(2)	Sampling switch resistance	-	-	-	1	kΩ
C_{ADC}(2)	Internal sample and hold capacitor	-	-	-	8	pF
t_{CAL}(2)(3)	Calibration time	f_{ADC} = 14 MHz	5.9			µs
		-	83			$1/f_{ADC}$

Figure 25. ADC accuracy characteristics



(1) Example of an actual transfer curve
(2) The ideal transfer curve
(3) End point correlation line

E_T = Total Unajusted Error: maximum deviation between the actual and ideal transfer curves.
E_O = Offset Error: maximum deviation between the first actual transition and the first ideal one.
E_G = Gain Error: deviation between the last ideal transition and the last actual one.
E_D = Differential Linearity Error: maximum deviation between actual steps and the ideal ones.
E_L = Integral Linearity Error: maximum deviation between any actual transition and the end point correlation line.

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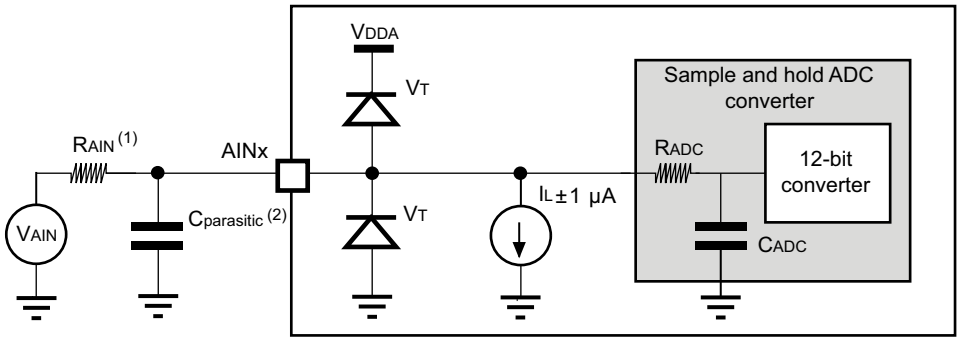
Figure 26. Typical connection diagram using the ADC



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1. Refer to *Table 55: ADC characteristics* for the values of R_{AIN}, R_{ADC} and C_{ADC}.
2. $C_{parasitic}$ represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 7 pF). A high $C_{parasitic}$ value will downgrade conversion accuracy. To remedy this, f_{ADC} should be reduced.

General PCB design guidelines

Power supply decoupling should be performed as shown in *Figure 12: Power supply scheme*. The 10 nF capacitor should be ceramic (good quality) and it should be placed as close as possible to the chip.

Table 65. I²C analog filter characteristics(1)

Symbol	Parameter	Min	Max	Unit
t_{AF}	Maximum width of spikes that are suppressed by the analog filter	50(2)	260(3)	ns

1. Guaranteed by design, not tested in production.
2. Spikes with widths below $t_{AF(min)}$ are filtered.
3. Spikes with widths above $t_{AF(max)}$ are not filtered

SPI/I²S characteristics

Unless otherwise specified, the parameters given in *Table 66* for SPI or in *Table 67* for I²S are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and supply voltage conditions summarized in *Table 23: General operating conditions*.

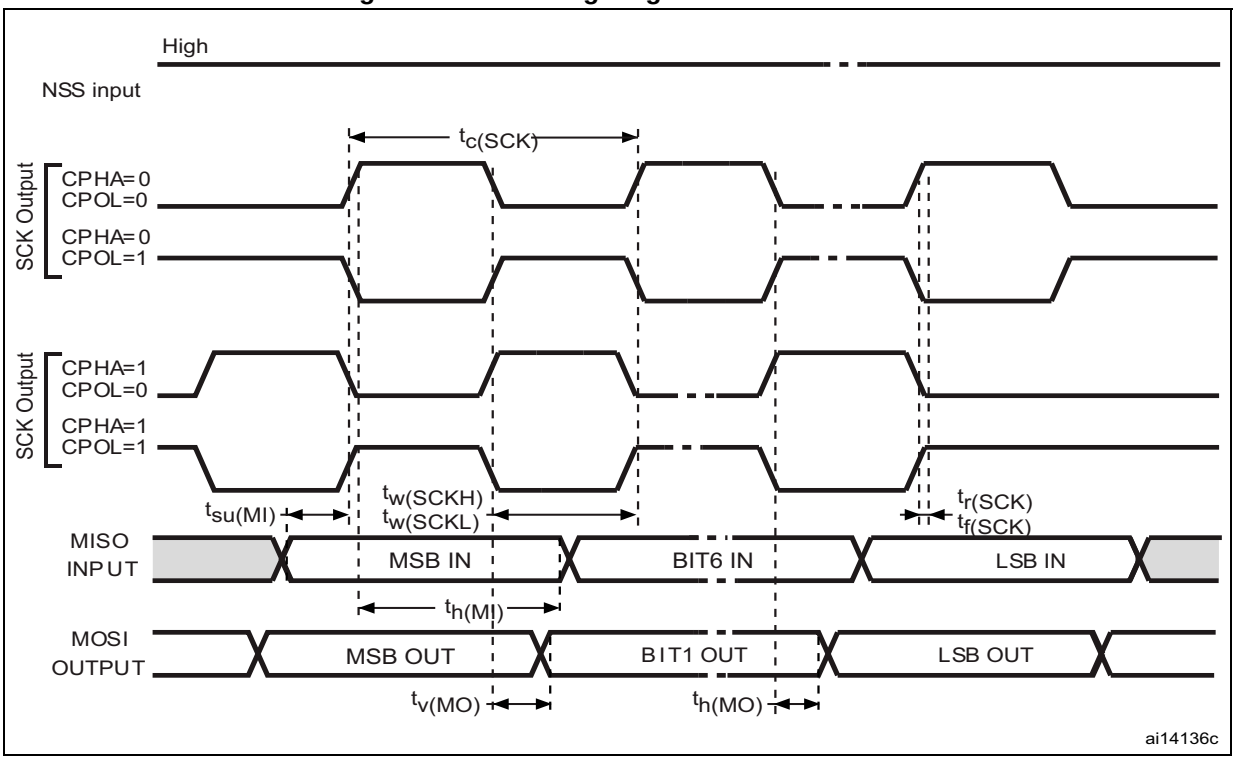
Refer to *Section 6.3.13: I/O port characteristics* for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO for SPI and WS, CK, SD for I²S).

Table 66. SPI characteristics(1)

Symbol	Parameter	Conditions	Min	Max	Unit
f_{SCK} $1/t_{c(SCK)}$	SPI clock frequency	Master mode	-	18	MHz
		Slave mode	-	18	
$t_{r(SCK)}$ $t_{f(SCK)}$	SPI clock rise and fall time	Capacitive load: C = 15 pF	-	6	ns
$t_{su(NSS)}$	NSS setup time	Slave mode	4Tpclk	-	ns
$t_{h(NSS)}$	NSS hold time	Slave mode	2Tpclk + 10	-	
$t_{w(SCKH)}$ $t_{w(SCKL)}$	SCK high and low time	Master mode, f_{PCLK} = 36 MHz, presc = 4	Tpclk/2 -2	Tpclk/2 + 1	
$t_{su(MI)}$ $t_{su(SI)}$	Data input setup time	Master mode	4	-	
		Slave mode	5	-	
$t_{h(MI)}$	Data input hold time	Master mode	4	-	
$t_{h(SI)}$		Slave mode	5	-	
$t_{a(SO)}$(2)	Data output access time	Slave mode, f_{PCLK} = 20 MHz	0	3Tpclk	
$t_{dis(SO)}$(3)	Data output disable time	Slave mode	0	18	
$t_{v(SO)}$	Data output valid time	Slave mode (after enable edge)	-	22.5	
$t_{v(MO)}$	Data output valid time	Master mode (after enable edge)	-	6	
$t_{h(SO)}$	Data output hold time	Slave mode (after enable edge)	11.5	-	
$t_{h(MO)}$		Master mode (after enable edge)	2	-	
DuCy(SCK)	SPI slave input clock duty cycle	Slave mode	25	75	%

1. Data based on characterization results, not tested in production.
2. Min time is for the minimum time to drive the output and the max time is for the maximum time to validate the data.
3. Min time is for the minimum time to invalidate the output and the max time is for the maximum time to put the data in Hi-Z

Figure 31. SPI timing diagram - master mode



1. Measurement points are done at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

Table 67. I^2S characteristics(1)

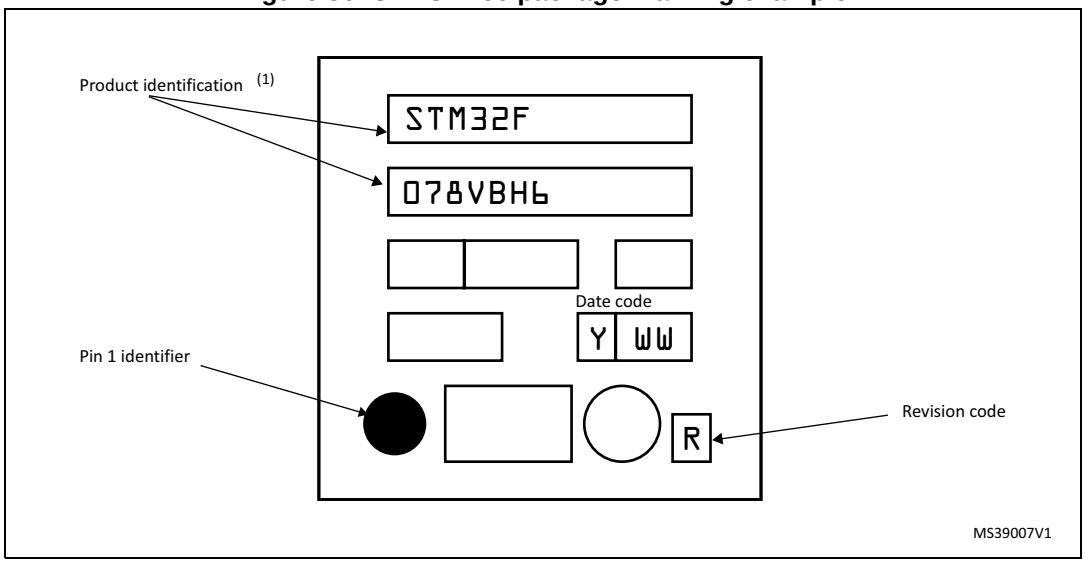
Symbol	Parameter	Conditions	Min	Max	Unit
f_{CK} $1/t_{c(CK)}$	I^2S clock frequency	Master mode (data: 16 bits, Audio frequency = 48 kHz)	1.597	1.601	MHz
		Slave mode	0	6.5	
$t_{r(CK)}$	I^2S clock rise time	Capacitive load C_L = 15 pF	-	10	ns
$t_{f(CK)}$	I^2S clock fall time		-	12	
$t_{w(CKH)}$	I^2S clock high time	Master f_{PCLK}= 16 MHz, audio frequency = 48 kHz	306	-	
$t_{w(CKL)}$	I^2S clock low time		312	-	
$t_{v(WS)}$	WS valid time	Master mode	2	-	
$t_{h(WS)}$	WS hold time	Master mode	2	-	
$t_{su(WS)}$	WS setup time	Slave mode	7	-	
$t_{h(WS)}$	WS hold time	Slave mode	0	-	
DuCy(SCK)	I^2S slave input clock duty cycle	Slave mode	25	75	%

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 36. UFBGA100 package marking example

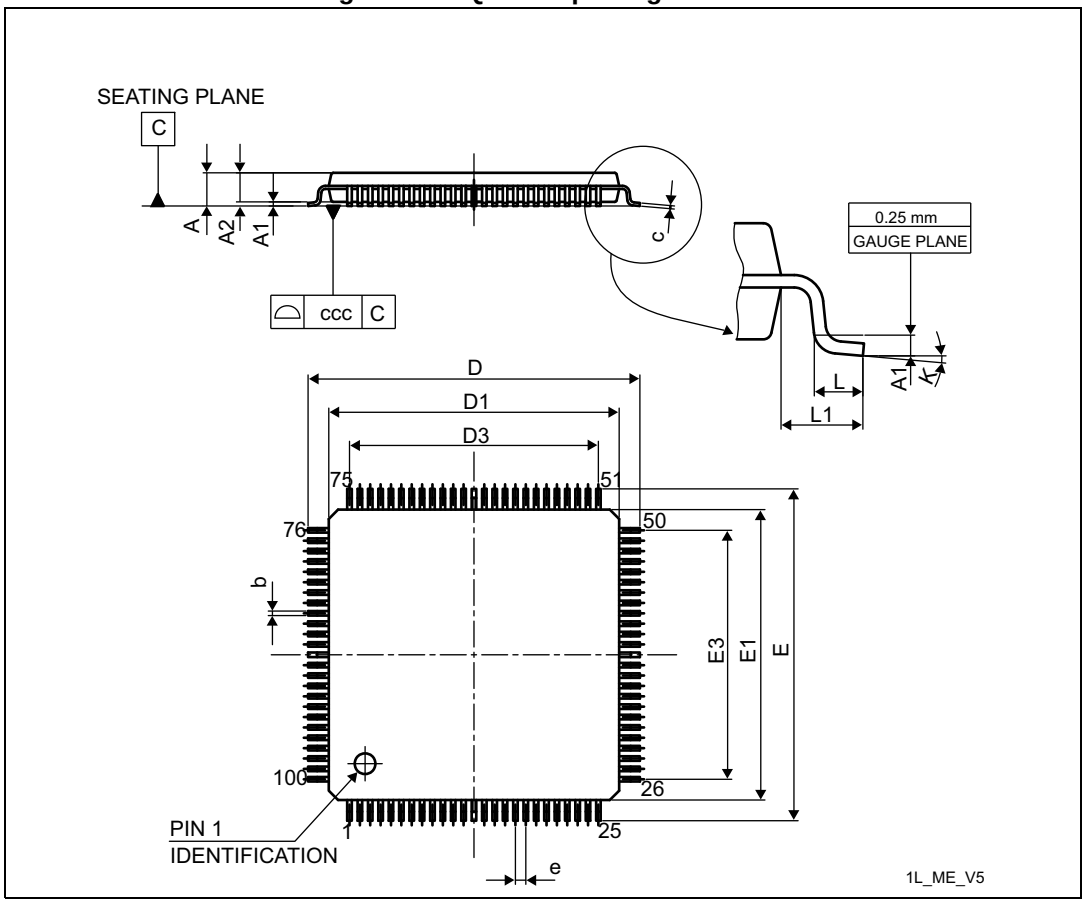


1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

7.2 LQFP100 package information

LQFP100 is a100-pin, 14 x 14 mm low-profile quad flat package.

Figure 37. LQFP100 package outline



1. Drawing is not to scale.

Table 71. LQPF100 package mechanical data

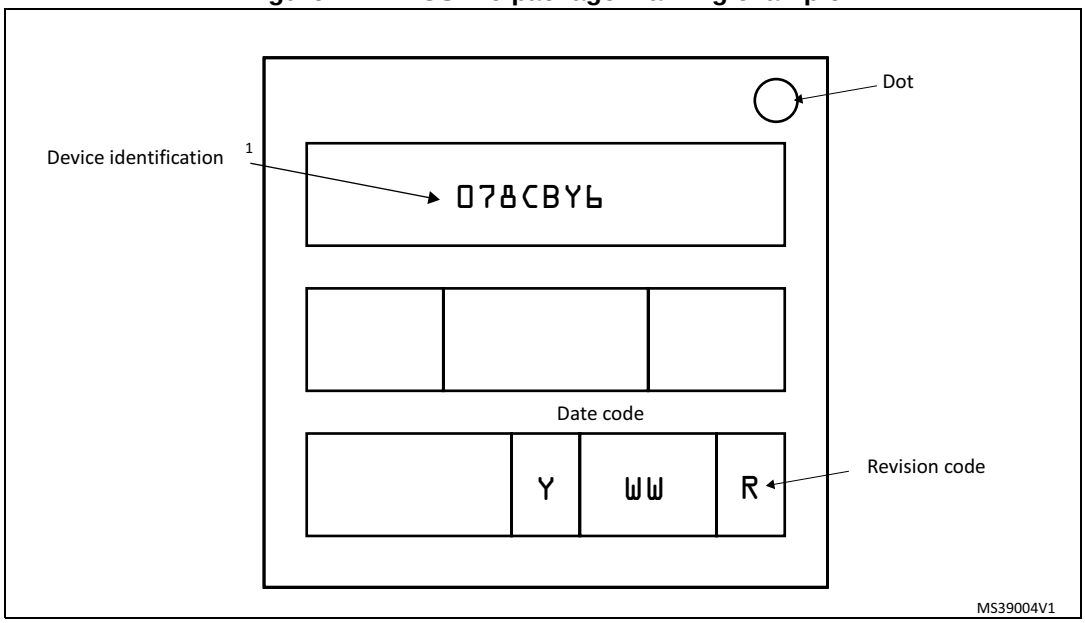
Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	15.800	16.000	16.200	0.6220	0.6299	0.6378
D1	13.800	14.000	14.200	0.5433	0.5512	0.5591
D3	-	12.000	-	-	0.4724	-
E	15.800	16.000	16.200	0.6220	0.6299	0.6378

Device marking

The following figure gives an example of topside marking orientation versus ball A1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 44. WLCSP49 package marking example



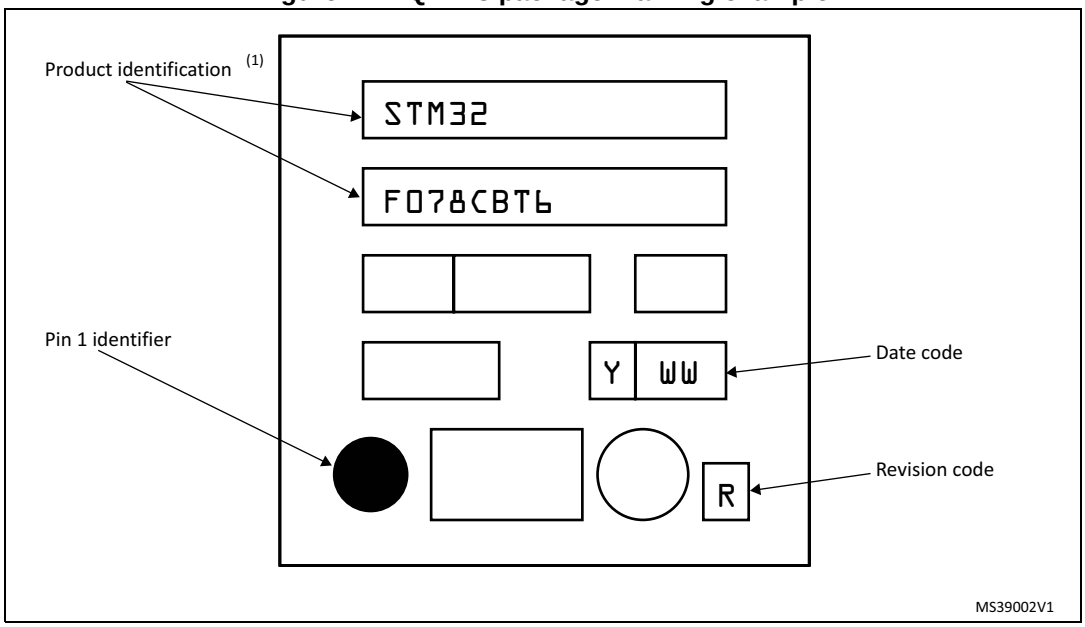
1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 47. LQFP48 package marking example



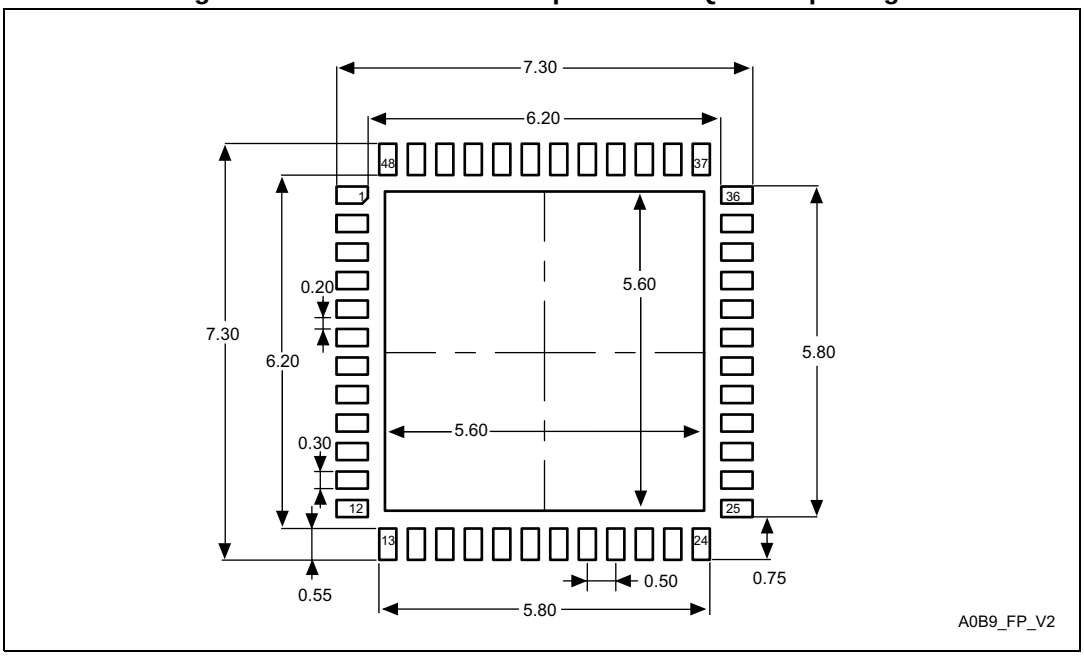
1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

Table 75. UFQFPN48 package mechanical data

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	0.500	0.550	0.600	0.0197	0.0217	0.0236
A1	0.000	0.020	0.050	0.0000	0.0008	0.0020
D	6.900	7.000	7.100	0.2717	0.2756	0.2795
E	6.900	7.000	7.100	0.2717	0.2756	0.2795
D2	5.500	5.600	5.700	0.2165	0.2205	0.2244
E2	5.500	5.600	5.700	0.2165	0.2205	0.2244
L	0.300	0.400	0.500	0.0118	0.0157	0.0197
T	-	0.152	-	-	0.0060	-
b	0.200	0.250	0.300	0.0079	0.0098	0.0118
e	-	0.500	-	-	0.0197	-
ddd	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 49. Recommended footprint for UFQFPN48 package



1. Dimensions are expressed in millimeters.

8 Ordering information

For a list of available options (memory, package, and so on) or for further information on any aspect of this device, please contact your nearest ST sales office.

Table 77. Ordering information scheme

Example: STM32 F 078 R B T 6 x

Device family

STM32 = ARM-based 32-bit microcontroller

Product type

F = General-purpose

Sub-family

078 = STM32F078xx

Pin count

C = 48/49 pins

R = 64 pins

V = 100 pins

User code memory size

B = 128 Kbyte

Package

H = UFBGA

T = LQFP

U = UFQFPN

Y = WLCSP

Temperature range

6 = –40 to 85 °C

7 = –40 to 105 °C

Options

xxx = code ID of programmed parts (includes packing type)

TR = tape and reel packing

blank = tray packing